



N-Channel Enhancement MOSFET

Features

- Drain-Source Breakdown Voltage V_{DSS} 60V
- Drain-Source On-Resistance
 $R_{DS(ON)} 20m\Omega$, at $V_{GS} = 10V$, $I_D = 20A$
 $R_{DS(ON)} 24m\Omega$, at $V_{GS} = 4.5V$, $I_D = 10A$
- *Continuous Drain Current* at $T_C = 25^\circ C$, $I_D = 35A$
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

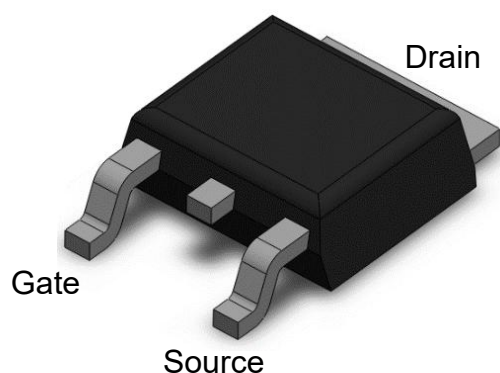
Description

The CTD6006-T52 is the N-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application.

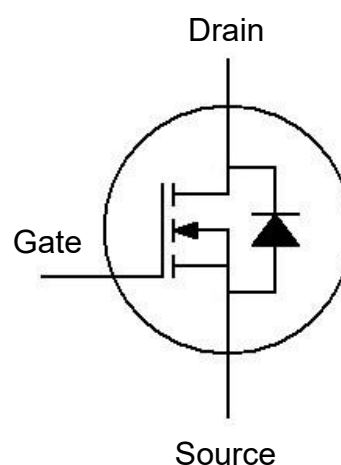
Applications

- Super Low Gate Charge
- 100% EAS Guaranteed
- Green Device Available
- Excellent CdV/dt effect decline

Package Outline



Schematic



**Absolute Maximum Rating at 25°C**

Symbol	Parameters	Test Conditions	Min	Note
V _{DS}	Drain-Source Voltage	60	V	
V _{GS}	Gate-Source Voltage	±20	V	
I _D	Continuous Drain Current @T _c =25°C	35	A	1
I _{DM}	Pulsed Drain Current	140	A	1
P _D	Total Power Dissipation @T _c =25°C	44.6	W	2
T _{STG}	Storage Temperature Range	-55 to 150	°C	
T _J	Operating Junction Temperature Range	-55 to 150	°C	

Thermal Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
R _{θJC}	Thermal Resistance Junction-Case		--	--	2.8	°C /W	1



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Electrical Characteristics $T_A = 25^\circ\text{C}$ (unless otherwise specified)

Static Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$B_{V_{DS}}$	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	60	-	-	V	
I_{DSS}	Drain-Source Leakage Current	$V_{DS} = 48V, V_{GS} = 0V$	-	-	1	μA	
I_{GSS}	Gate-Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	± 100	nA	

On Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS} = 10V, I_D = 20A$	-	-	20	m Ω	3
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS} = 4.5V, I_D = 10A$	-	-	24	m Ω	3
$V_{GS(th)}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\mu A$	1.2	-	2.5	V	3

Dynamic Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
C_{ISS}	Input Capacitance	$V_{GS} = 0V,$	-	2423	-	pF	
C_{OSS}	Output Capacitance	$V_{DS} = 15V$	-	145	-		
C_{RSS}	Reverse Transfer Capacitance	$f = 1MHz$	-	97	-		

Switching Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$T_{D(ON)}$	Turn-On Delay Time	$V_{DS} = 30V, R_G = 3.3\Omega$ $V_{GS} = 10V, R_L = 2\Omega$	-	7.2	-	ns	
T_R	Rise Time		-	50	-		
$T_{D(OFF)}$	Turn-Off Delay Time		-	36.4	-		
T_F	Fall Time		-	7.6	-		
Q_G	Total Gate Charge	$V_{DS} = 48V,$	-	19.3	-	nC	
Q_{GS}	Gate-Source Charge	$V_{GS} = 4.5V,$	-	7.1	-		
Q_{GD}	Gate-Drain (Miller) Charge	$I_D = 15A$	-	7.6	-		

**Drain-Source Diode Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V _{SD}	Body Diode Forward Voltage	V _{GS} = 0V, I _{SD} = 1.0A	-	-	1.0	V	1
I _{SD}	Body Diode Continuous Current		-	-	35	A	1

Note:

1. The power dissipation is limited by 150°C junction temperature.
2. The data tested by pulsed , pulse width $\leq 300 \mu s$, duty cycle $\leq 2\%$
3. Thermal Resistance follow JESD51-3.



Typical Characteristic Curves

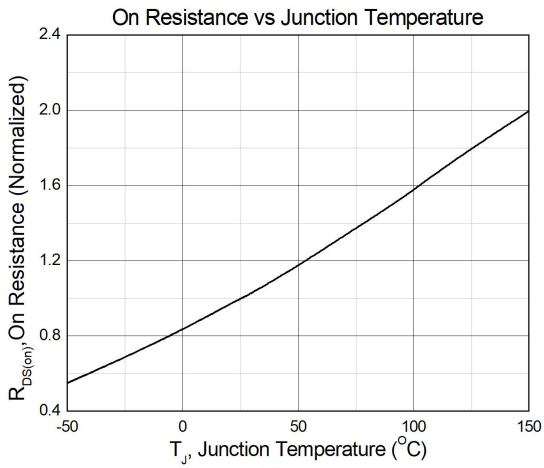


Figure 1

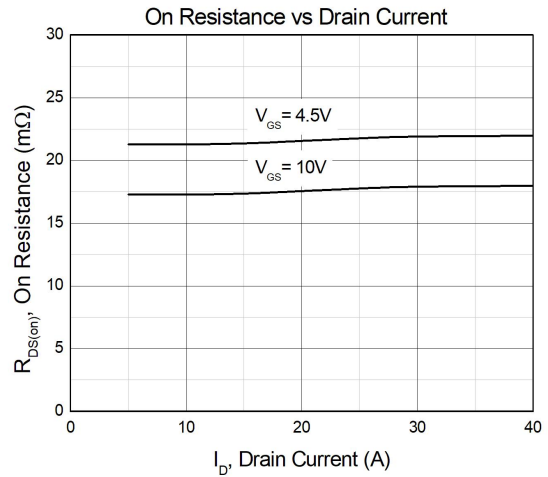


Figure 2

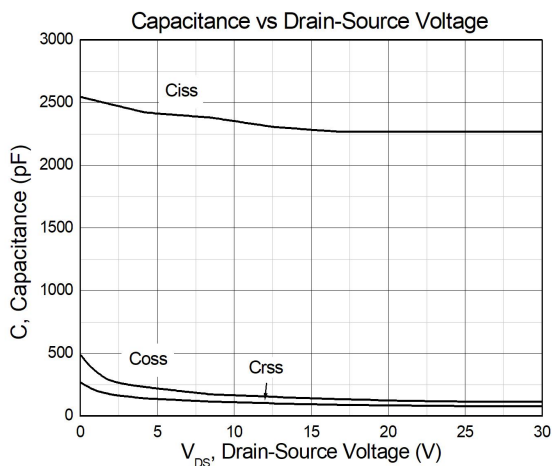


Figure 3

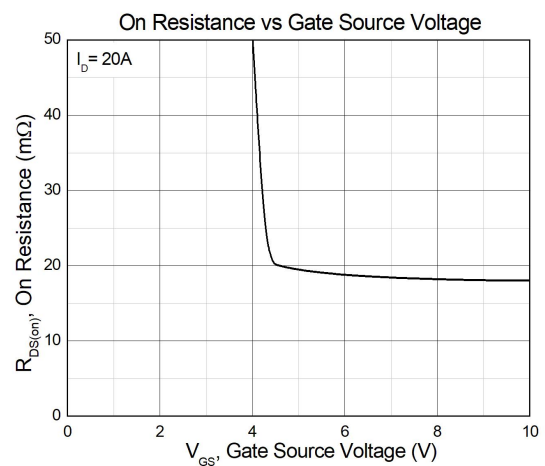


Figure 4

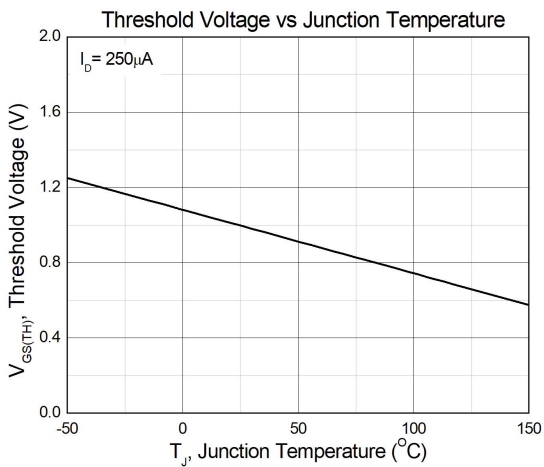


Figure 5

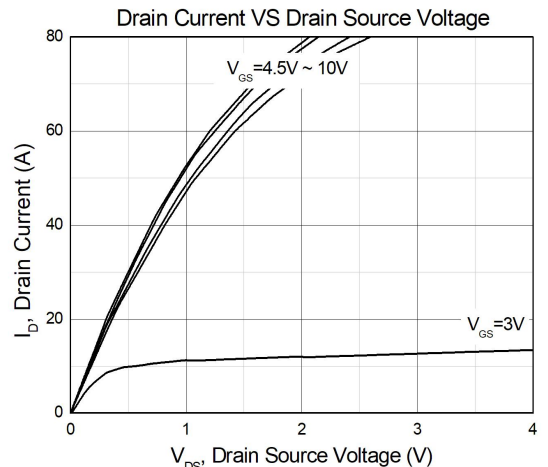


Figure 6



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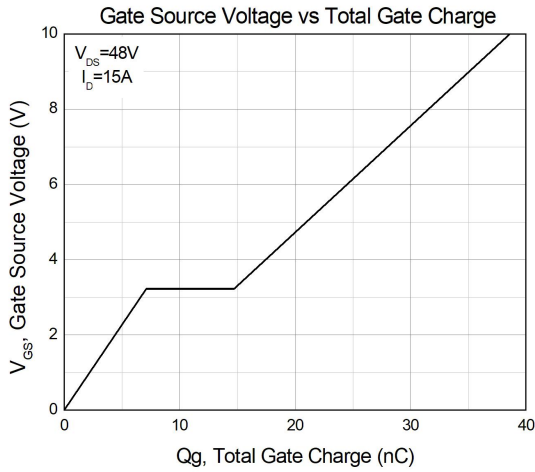


Figure 7

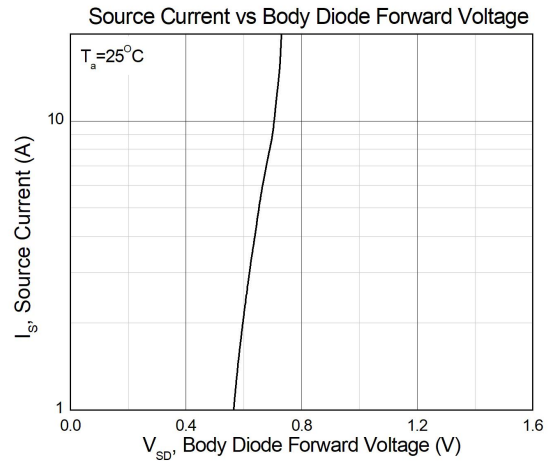


Figure 8

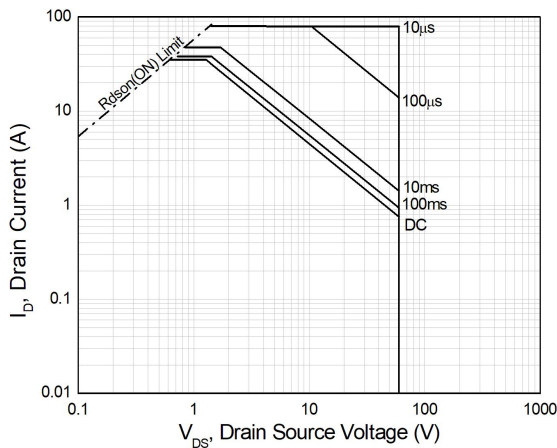


Figure 9

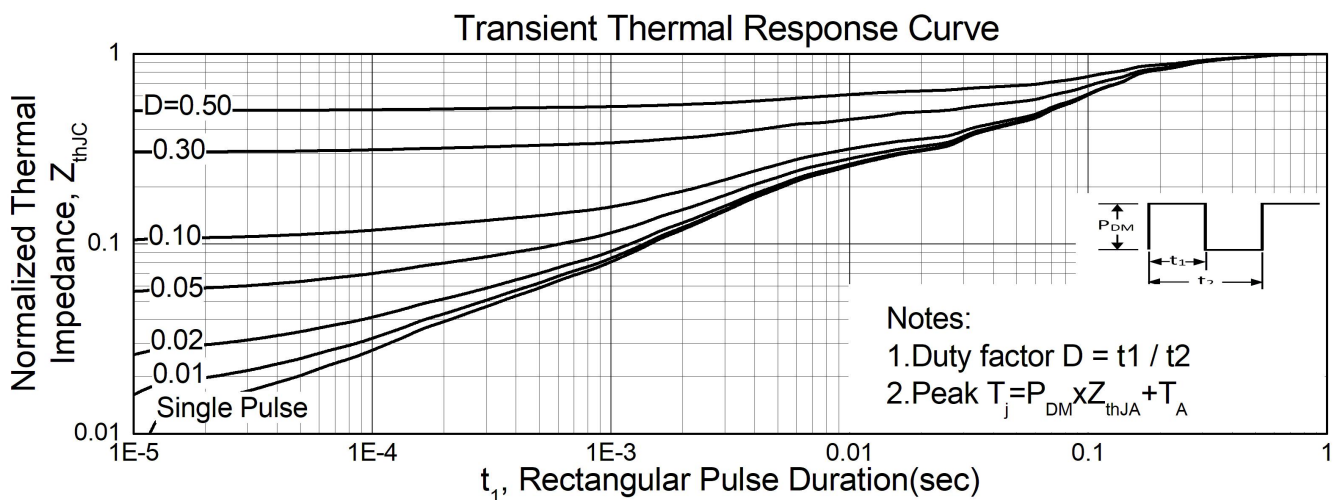


Figure 10



Test Circuits & Waveforms

Figure 11: Gate Charge Test Circuit

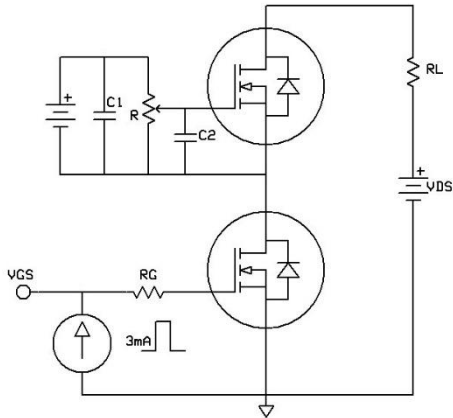


Figure 12: Gate Charge Waveform

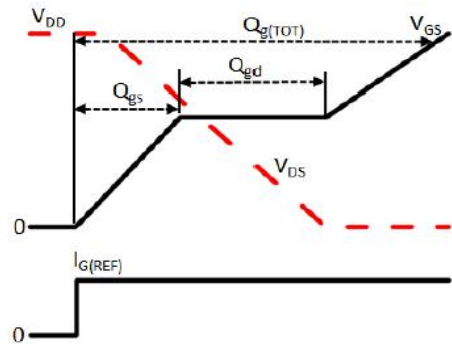


Figure 13: Switching Time Test Circuit

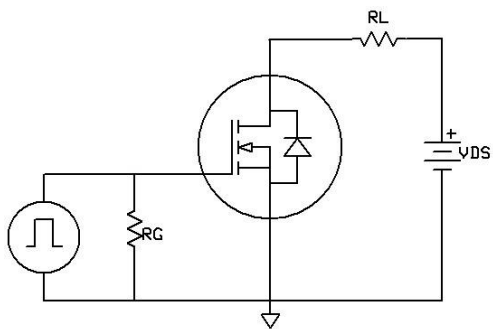
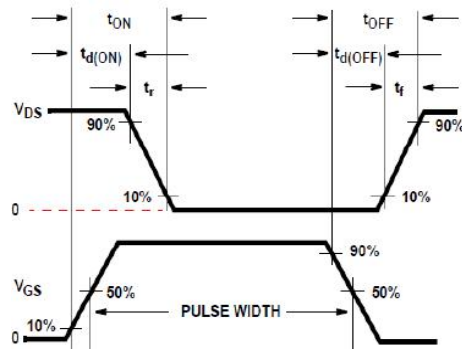
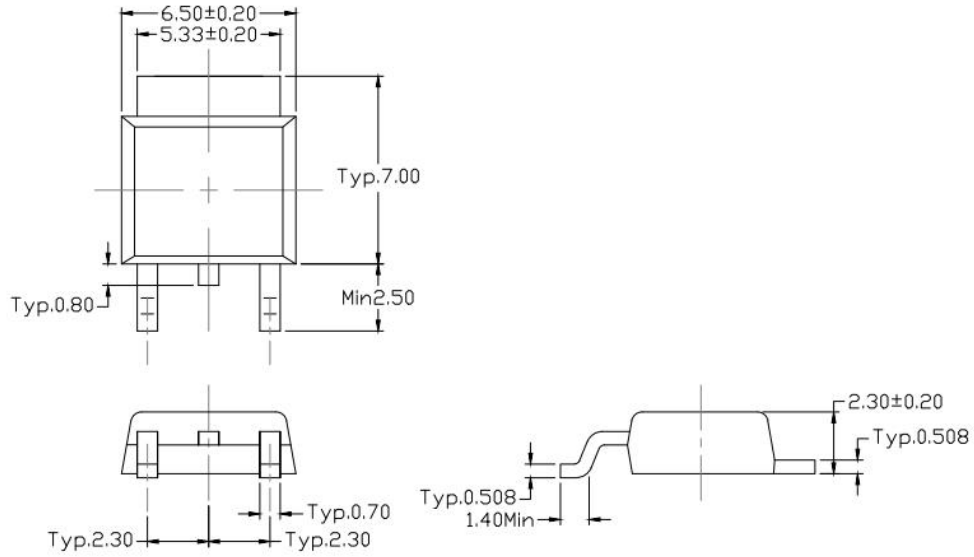


Figure 14: Switching Time Waveform



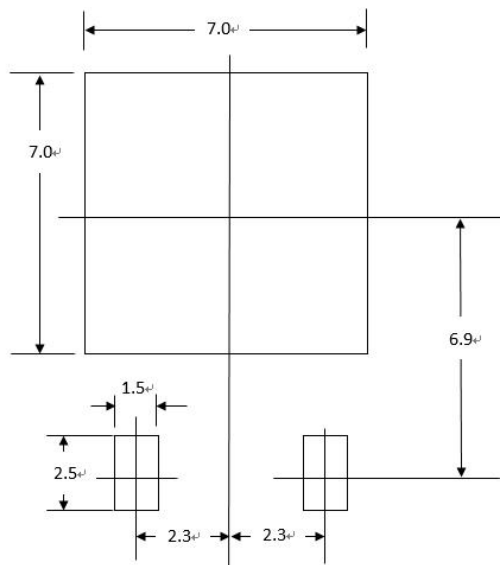


Package Dimension (TO-252)



Dimensions in mm unless otherwise stated

Recommended pad layout for surface mount leadform



Dimensions in mm unless otherwise stated

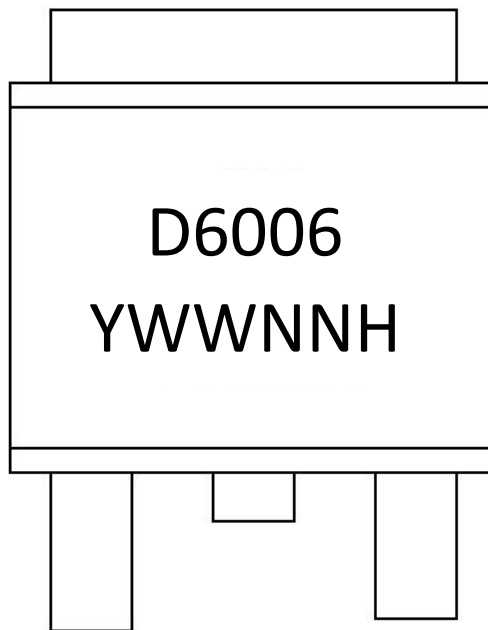


CTD6006-T52

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Marking Information

D : Package type
6006 : Device Number
Y : Fiscal Year
WW : Work Week
NN : Serial number
H : Package code



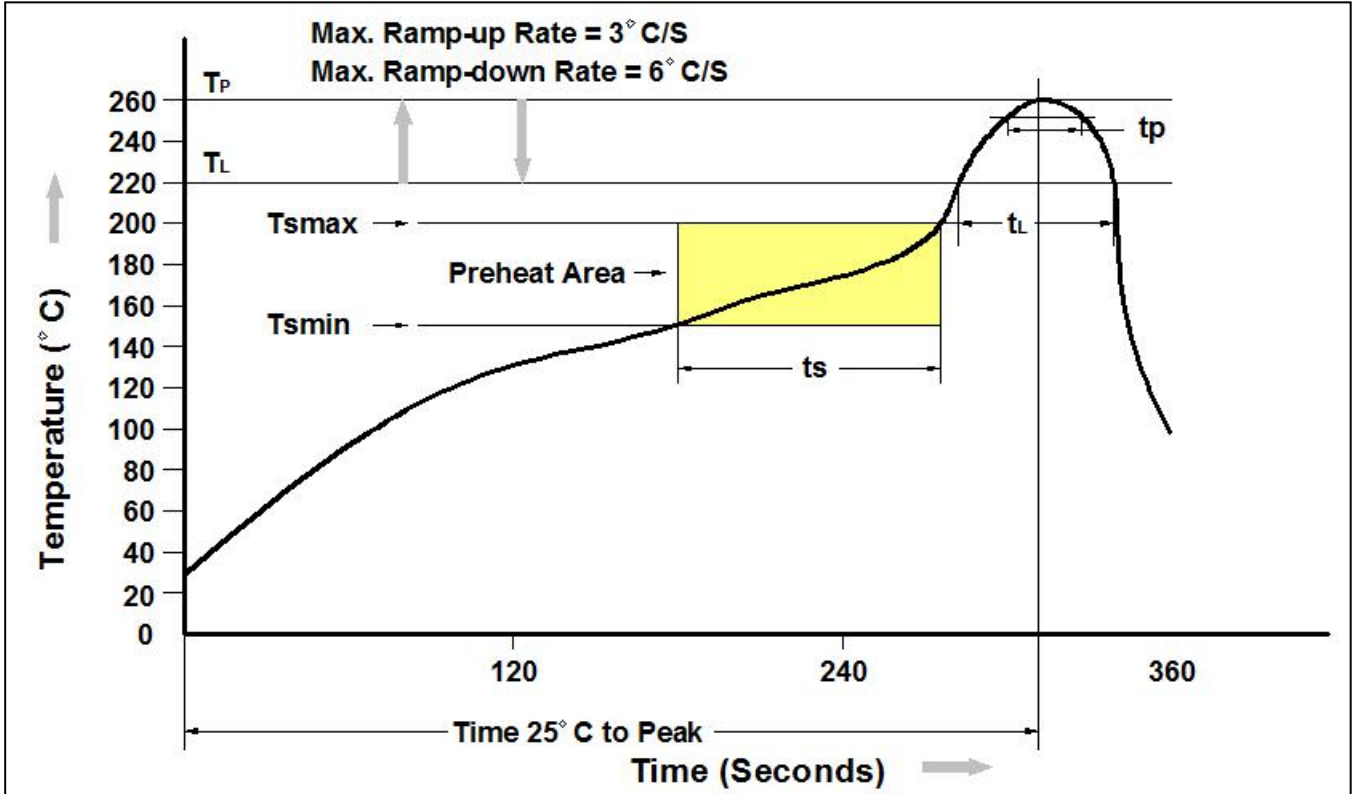
Ordering Information

Part Number	Description	Quantity
CTD6006-T52	TO-252 Reel	2500 pcs



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Reflow Profile



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Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T Amin)	150°C
Temperature Max. (Tsmax)	200°C
Time (ts) from (T Amin to Tsmax)	60-120 seconds
Ramp-up Rate (tL to tP)	3°C/second max.
Liquidous Temperature (TL)	217°C
Time (tL) Maintained Above (TL)	60 – 150 seconds
Peak Body Package Temperature	260°C +0°C / -5°C
Time (tp) within 5°C of 260°C	30 seconds
Ramp-down Rate (TP to TL)	6°C/second max
Time 25°C to Peak Temperature	8 minutes max.

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CTD6006-T52

N-Channel Enhancement MOSFET

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